

Notice of References Cited

Application/Control No.

10/784,979

Applicant(s)/Patent Under
Reexamination
YACH ET AL.

Examiner

SHEW-FEN LIN

Art Unit

2166

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*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,973,612	10-1999	Deo et al.	340/7.58
*	B	US-6,990,333	01-2006	Andrew et al.	455/414.1
*	C	US-7,243,130	07-2007	Horvitz et al.	709/207
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FOREIGN PATENT DOCUMENTS

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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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